

Notice of References Cited	Application/Control No. 10/002,175		Applicant(s)/Patent Under Reexamination BOWEN, NEAL M.	
	Examiner Lynne Edmondson		Art Unit 1725	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,273,321	08-2001	Koduri, Sreenivasan	228/4.5
*	B	US-4,445,633	05-1984	Bonham, Jr., Harry B.	228/102
*	C	US-5,060,843	10-1991	Yasuzato et al.	228/179.1
*	D	US-4,327,860	05-1982	Kirshenboin et al.	228/180.5
*	E	US-6,189,765	02-2001	Moon, Young Ku	228/102
*	F	US-6,476,506	11-2002	O'Connor et al.	257/786
*	G	US-2003/0137042	07-2003	Mess et al.	257/686
*	H	US-6,091,140	07-2000	Toh et al.	257/691
*	I	US-6,561,411	05-2003	Lee, Chun-Chi	228/180.5
*	J	US-2003/0205725	11-2003	Masumoto et al.	257/200
*	K	US-5,498,767	03-1996	Huddleston et al.	716/12
*	L	US-5,054,194	10-1991	Pollock, Randy	29/840
*	M	US-5,702,049	12-1997	Biggs et al.	228/105

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP-07-202069-A	08-1995	Japan	Kondo	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.